

Supplementary information for:

**The epitaxial growth of lead-phthalocyanine on copper halogen
compounds as the origin of templating effects**

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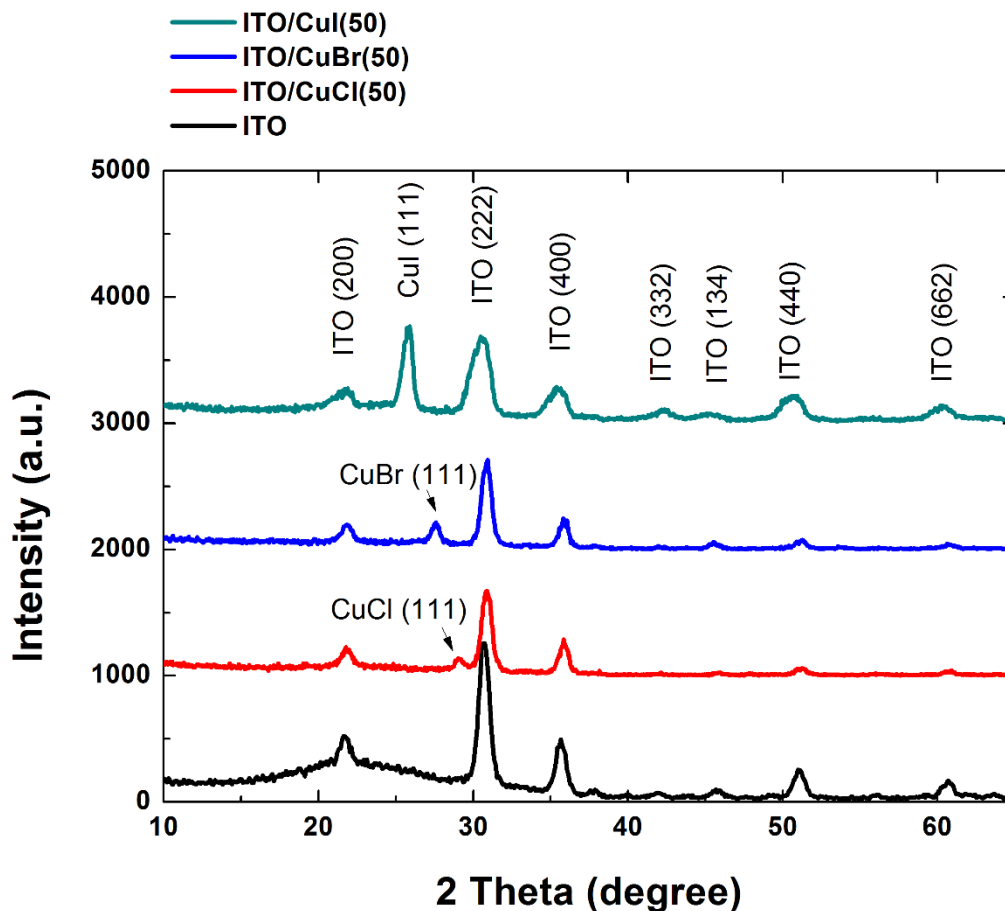


Figure S1. The X-ray diffraction profiles of ITO (black), ITO/CuCl (50 nm) (red), ITO/CuBr (50 nm) (blue), ITO/CuI (50 nm) (green). X-ray diffraction (XRD) measurements were done by D8 Advance diffractometer (Bruker) using Cu K α radiation at incident angle of 1°. The films were deposited on ITO substrates.